

# **MOSFET**

### OptiMOS<sup>™</sup>FD Power-Transistor, 220 V

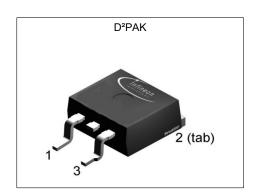
### **Features**

- N-channel, normal level

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  Fast Diode (FD) with reduced Q<sub>rr</sub>
  Optimized for hard commutation ruggedness
  Very low on-resistance R<sub>DS(on)</sub>
  175 °C operating temperature
  Pb-free lead plating; RoHS compliant
  Qualified according to JEDEC<sup>1)</sup> for target application
  Halogen-free according to IEC61249-2-21



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Parameter	Value	Unit					
<b>V</b> <sub>DS</sub>	220	V					
R <sub>DS(on),max</sub>	15.6	mΩ					
I <sub>D</sub>	72	A					











Type / Ordering Code	Package	Marking	Related Links
IPB156N22NFD	PG-TO 263-3	156N22NF	-



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# 1 Maximum ratings at $T_A$ =25 °C, unless otherwise specified

Table 2 **Maximum ratings** 

Davamatav	Cymphal	Values			11	Nata / Table Occupité au	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Continuous drain current	I <sub>D</sub>	-	-	72 56	А	T <sub>C</sub> =25 °C T <sub>C</sub> =100 °C	
Pulsed drain current <sup>1)</sup>	I <sub>D,pulse</sub>	-	-	288	Α	<i>T</i> <sub>C</sub> =25 °C	
Avalanche energy, single pulse <sup>2)</sup>	<b>E</b> AS	-	-	400	mJ	$I_{\rm D}$ =50 A, $R_{\rm GS}$ =25 $\Omega$	
Gate source voltage	V <sub>GS</sub>	-20	-	20	V	-	
Power dissipation	P <sub>tot</sub>	-	-	300	W	<i>T</i> <sub>C</sub> =25 °C	
Operating and storage temperature	T <sub>j</sub> , T <sub>stg</sub>	-55	-	175	°C	IEC climatic category; DIN IEC 68-1: 55/175/56	

#### 2 Thermal characteristics

Table 3 Thermal characteristics

Davamatav	Cumbal	Values			1114		
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Thermal resistance, junction - case	R <sub>thJC</sub>	-	0.3	0.5	K/W	-	
Thermal resistance, junction - ambient, minimal footprint	R <sub>thJA</sub>	-	-	62	K/W	-	
Thermal resistance, junction - ambient, 6 cm <sup>2</sup> cooling area <sup>3)</sup>	R <sub>thJA</sub>	-	-	40	K/W	-	

#### 3 **Electrical characteristics**

Table 4 **Static characteristics** 

Barranatan	0		Values				
Parameter	Symbol	Min.	Min. Typ.		Unit	Note / Test Condition	
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	220	-	-	V	V <sub>GS</sub> =0 V, I <sub>D</sub> =1 mA	
Gate threshold voltage	$V_{\rm GS(th)}$	2	3	4	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =270 μA	
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.1 10	1 100	μΑ	V <sub>DS</sub> =176 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =25 °C V <sub>DS</sub> =176 V, V <sub>GS</sub> =0 V, T <sub>j</sub> =125 °C	
Gate-source leakage current	I <sub>GSS</sub>	-	1	100	nA	V <sub>GS</sub> =20 V, V <sub>DS</sub> =0 V	
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	12.9	15.6	mΩ	V <sub>GS</sub> =10 V, I <sub>D</sub> =50 A	
Gate resistance	R <sub>G</sub>	-	2.8	-	Ω	-	
Transconductance	<b>g</b> fs	60	119	-	S	V <sub>DS</sub>  >2 I <sub>D</sub>  R <sub>DS(on)max</sub> , I <sub>D</sub> =72 A	

See Diagran 3 for more detailed information
 See Diagran 13 for more detailed information
 Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.



**Dynamic characteristics** Table 5

Downworton.	Complete	Values			I I m i 4	Nata / Tank Can diking	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Input capacitance <sup>1)</sup>	Ciss	-	5210	6930	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =110 V, f=1 MHz	
Output capacitance <sup>1)</sup>	Coss	-	343	456	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =110 V, f=1 MHz	
Reverse transfer capacitance	Crss	-	6.2	-	pF	V <sub>GS</sub> =0 V, V <sub>DS</sub> =110 V, f=1 MHz	
Turn-on delay time	$t_{ m d(on)}$	-	15	-	ns	$V_{\rm DD}$ =110 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =36 A, $R_{\rm G,ext}$ =1.6 $\Omega$	
Rise time	t <sub>r</sub>	-	15	-	ns	$V_{\rm DD}$ =110 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =36 A, $R_{\rm G,ext}$ =1.6 $\Omega$	
Turn-off delay time	$t_{ m d(off)}$	-	45	-	ns	$V_{\rm DD}$ =110 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =36 A, $R_{\rm G,ext}$ =1.6 $\Omega$	
Fall time	t <sub>f</sub>	-	15	-	ns	$V_{\rm DD}$ =110 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =36 A, $R_{\rm G,ext}$ =1.6 $\Omega$	

Gate charge characteristics<sup>2)</sup> Table 6

Dougnator	Comple al		Values			Nata / Table Open Hittage	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Gate to source charge	Q <sub>gs</sub>	-	25	-	nC	$V_{\rm DD}$ =110 V, $I_{\rm D}$ =72 A, $V_{\rm GS}$ =0 to 10 V	
Gate to drain charge	$Q_{ m gd}$	-	9.4	-	nC	$V_{\rm DD}$ =110 V, $I_{\rm D}$ =72 A, $V_{\rm GS}$ =0 to 10 V	
Switching charge	Q <sub>sw</sub>	-	19	-	nC	$V_{\rm DD}$ =110 V, $I_{\rm D}$ =72 A, $V_{\rm GS}$ =0 to 10 V	
Gate charge total <sup>1)</sup>	Qg	-	66	87	nC	$V_{\rm DD}$ =110 V, $I_{\rm D}$ =72 A, $V_{\rm GS}$ =0 to 10 V	
Gate plateau voltage	V <sub>plateau</sub>	-	4.8	-	V	$V_{\rm DD}$ =110 V, $I_{\rm D}$ =72 A, $V_{\rm GS}$ =0 to 10 V	
Output charge <sup>1)</sup>	Qoss	-	153	203	nC	V <sub>DD</sub> =110 V, V <sub>GS</sub> =0 V	

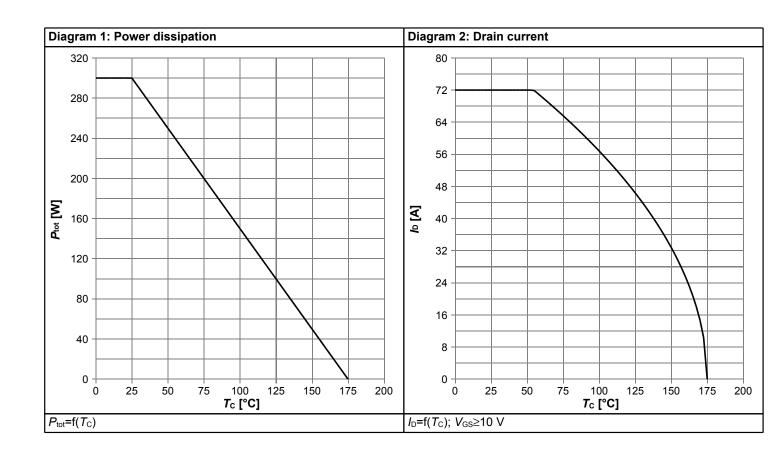
#### Reverse diode<sup>3)</sup> Table 7

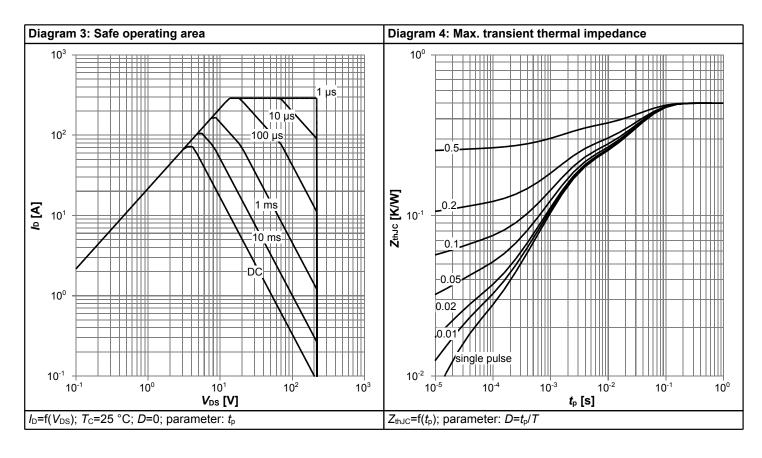
Davameter	Cumbal	Values			l lmi4	Note / Test Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Diode continous forward current	Is	-	-	72	Α	<i>T</i> <sub>C</sub> =25 °C	
Diode pulse current <sup>4)</sup>	I <sub>S,pulse</sub>	-	-	288	Α	T <sub>C</sub> =25 °C	
Diode hard commutation current <sup>1)</sup>	I <sub>S,hard</sub>	-	-	144	Α	T <sub>C</sub> =25 °C, d <i>i</i> <sub>F</sub> /d <i>t</i> =1500 A/μs	
Diode forward voltage	V <sub>SD</sub>	-	0.91	1.2	V	V <sub>GS</sub> =0 V, I <sub>F</sub> =72 A, T <sub>j</sub> =25 °C	
Reverse recovery time	t <sub>rr</sub>	-	140	-	ns	$V_R$ =100 V, $I_F$ = 50 A, $di_F/dt$ =100 A/ $\mu$ s	
Reverse recovery charge	Q <sub>rr</sub>	-	340	-	nC	$V_R$ =100 V, $I_F$ = 50 A, $di_F/dt$ =100 A/ $\mu$ s	

Define by design. Not subject to production test
 See "Gate charge waveforms" for parameter definition
 Maximum allowed hard-commutated current through diode at di/dt=1500 A/µs
 Diode pulse current is defined by thermal and/or package limits

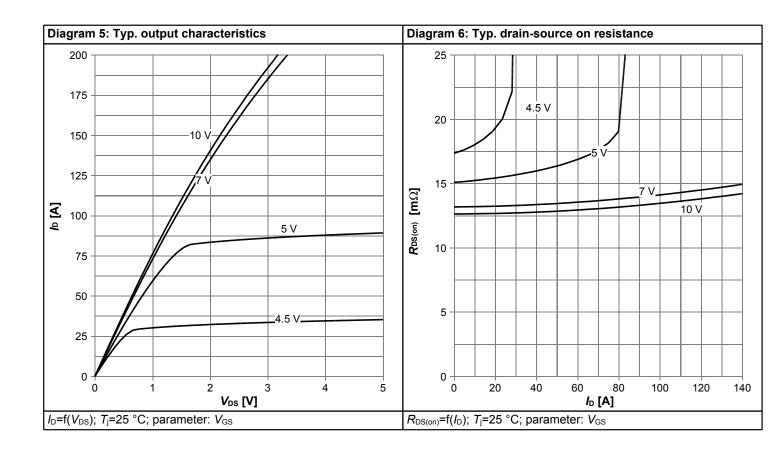


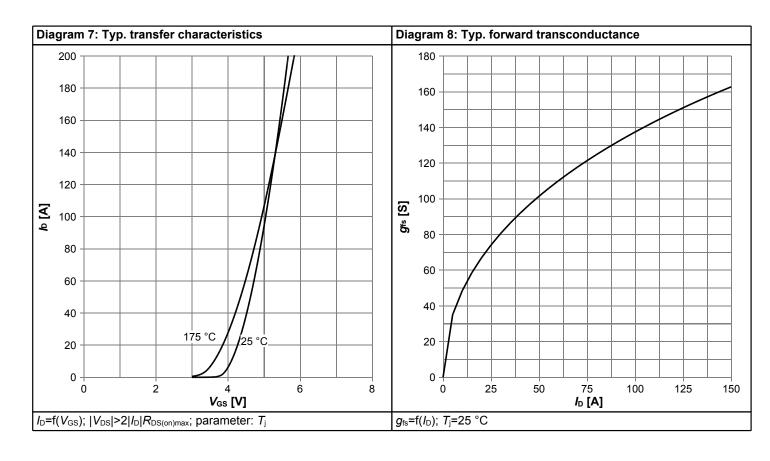
# 4 Electrical characteristics diagrams



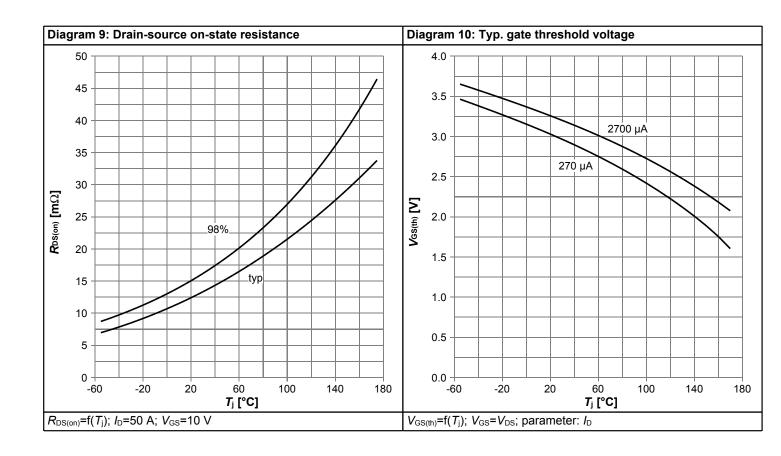


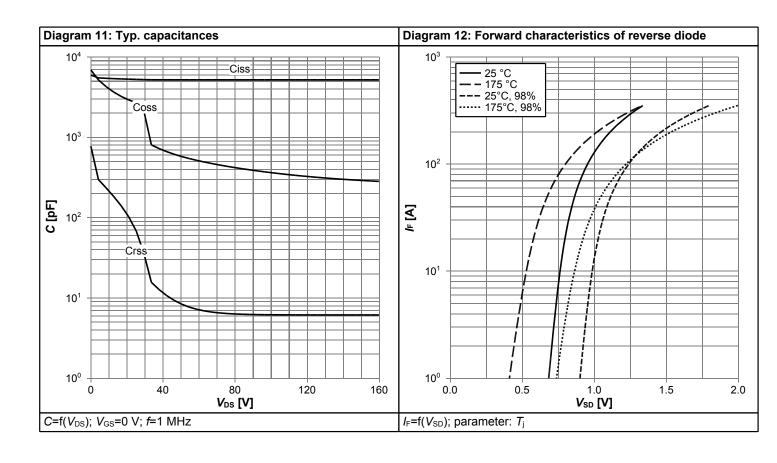




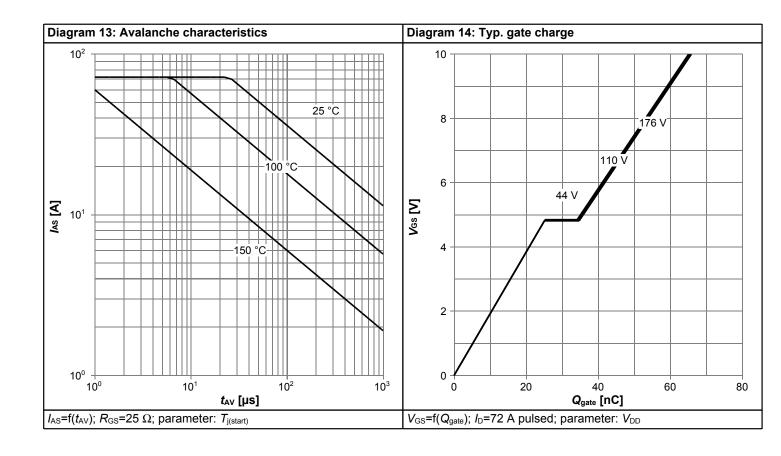


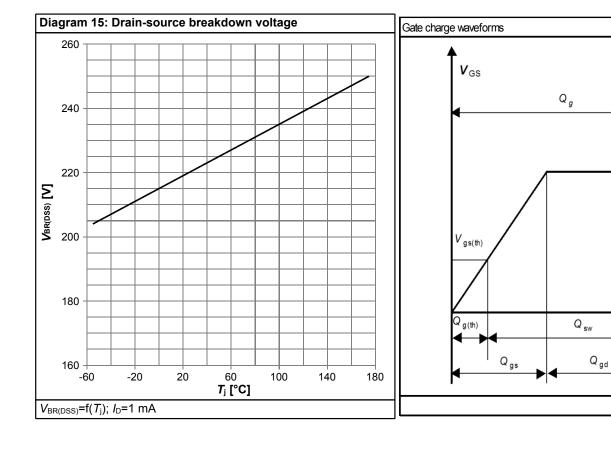






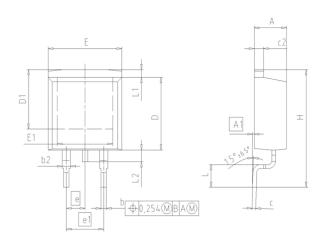


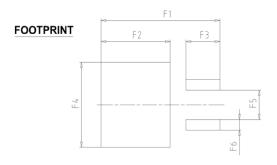






# 5 Package Outlines





DIM	MILLIN	METERS	INCH	HES		
DIM	MIN	MAX	MIN			
Α	4.30	4.57	0.169	0.180		
A1	0.00	0.25	0.000	0.010		
b	0.65	0.85	0.026	0.033		
b2	0.95	1.15	0.037	0.045		
С	0.33	0.65	0.013	0.026		
c2	1.17	1.40	0.046	0.055		
D	8.51	9.45	0.335	0.372		
D1	7.10	7.90	0.280	0.311		
E	9.80	10.31	0.386	0.406		
E1	6.50	8.60	0.256	0.339		
е	2.	54	0.100			
e1	5.	08	0.200			
N		2	2			
н	14.61	15.88	0.575	0.625		
L	2.29	3.00	0.090	0.118		
L1	0.70	1.60	0.028	0.063		
L2	1.00	1.78	0.039	0.070		
F1	16.05	16.25	0.632	0.640		
F2	9.30	9.50	0.366	0.374		
F3	4.50	4.70	0.177	0.185		
F4	10.70	10.90	0.421	0.429		
F5	3.65	3.85	0.144	0.152		
F6	1.25	1.45	0.049	0.057		



Figure 1 Outline PG-TO 263-3, dimensions in mm/inches



### **Revision History**

IPB156N22NFD

Revision: 2017-06-19, Rev. 2.0

Previous Revision

Revision	Date	Subjects (major changes since last revision)			
2.0	2017-06-19	Release of final version			

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